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- Meets or Exceeds the Requirements of ANSI Standard EIA/TIA-422-B and ITU **Recommendation V.11**
- Designed to Operate Up to 20 Mbaud
- 3-State TTL Compatible
- Single 5-V Supply Operation
- High Output Impedance in Power-Off Condition
- Complementary Output Enable Inputs
- Improved Replacement for the AM26LS31

description

These four differential line drivers are designed for data transmission over twisted-pair or parallel-wire transmission lines. They meet the requirements of ANSI Standard EIA/TIA-422-B and ITU Recommendations V.11 and are compatible with 3-state TTL circuits. Advanced low-power Schottky technology provides high speed without the usual power penalties. Standby supply current is typically only 26 mA, while typical propagation delay time is less than 10 ns.

High-impedance inputs maintain low input currents, less than 1 µA for a high level and less than 100 µA for a low level. Complementary enable inputs, G and \overline{G} , allow these devices to be enabled at either a high input level or low input level. The SN75ALS192 is capable of data rates in excess of 20 megabits per second and is designed to operate with the SN75ALS193 quadruple line receiver. The SN55ALS192 is also capable of data rates in excess of 20 megabits per second and designed to operate with the SN55ALS193; however, it may be limited to a lower bit rate based on the temperature (refer to the dissipation rating table and Figure 15).

The SN55ALS192 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN75ALS192 is characterized for operation from 0°C to 70°C.

SN55ALS192 J OR W PACKAG	E
SN75ALS192 D OR N PACKAG	Ε
(TOP VIEW)	

16] V _{CC} 15] 4A 14] 4Y 13] 4Z 12] G 11] 3Z 10] 3Y
9] 3A

SN55ALS192 ... FK PACKAGE (TOP VIEW)



NC - No internal connection

FUNCTION TABLE (each driver)

INPUT	ENA	BLES	OUT	PUTS	
A	G	G	Y	Z	
н	н	Х	Н	L	
L	н	Х	L	н	
н	Х	L	н	L	
L	Х	L	L	Н	
Х	L	Н	Z	Z	

H = hiah level.I = low level.

Z = high impedance (off), X = irrelevant

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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logic symbol[†]



logic diagram (positive logic)



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, N, and W packages.

schematics of inputs and outputs





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{CC} (see Note 1)		
Input voltage, V _I		
Off-state output voltage		
Continuous total dissipation		See Dissipation Rating Table
Operating free-air temperature range, T _A :	SN55ALS192	– 55°C to 125°C
	SN75ALS192	0°C to 70°C
Storage temperature range, T _{sta}		– 65°C to 150°C
Case temperature for 60 seconds, T _C : FK	package	260°C
Lead temperature 1,6 mm (1/16 inch) from	case for 60 seconds: J package	300°C
Lead temperature 1,6 mm (1/16 inch) from	case for 10 seconds: D, N, or W pa	ackage 260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values except differential output voltage, VOD, are with respect to network ground terminal.

DISSIPATION RATING TABLE								
PACKAGE	$T_A \le 25^{\circ}C$ POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 125°C POWER RATING				
D	950 mW	7.6 mW/°C	608 mW	N/A				
FK	1375 mW	11.0 mW/°C	880 mW	275 mW				
J‡	1375 mW	11.0 mW/°C	880 mW	275 mW				
Ν	1150 mW	9.2 mW/°C	736 mW	N/A				
W	1000 mW	8.0 mW/°C	640 mW	200 mW				

[†] In the J package, the SN55ALS192 chips are either alloy or silver glass mounted.

recommended operating conditions

	SN55ALS192			SN75ALS192			
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.5	5	5.5	4.75	5	5.25	V
High level input voltage, VIH	2			2			V
Low-level input voltage, VIL			0.8			0.8	V
High-level output current, IOH			- 20			- 20	mA
Low-level output current, IOL			20			20	mA
Operating free-air temperature, T _A	- 55		125	0		70	°C



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED		TERT CONDITIONIST		SN55ALS192			SN7								
	FARAMETER TEST CONDITIONST		NDITIONS	MIN	TYP‡	MAX	MIN	TYP‡	MAX						
VIK	Input clamp voltage	$V_{CC} = MIN$, $I_I = -18 \text{ mA}$				-1.5			-1.5	V					
VOH	High-level output voltage	$V_{CC} = MIN,$	I _{OH} = - 20 mA	2.4			2.5			V					
VOL	Low-level output voltage	$V_{CC} = MIN,$	I _{OL} = 20 mA			0.5			0.5	V					
Vo	Output voltage	$V_{CC} = MAX,$	IO = 0	0		6	0		6	V					
VOD1	Differential output voltage	$V_{CC} = MIN$,	I <mark>O</mark> = 0	1.5		6	1.5		6	V					
IVOD2	Differential output voltage	R _L = 100 Ω,	See Figure 1	1/2 V _{OD1} or 2§			1/2 V _{OD1} or 2§			V					
	Change in magnitude of differential output voltage \P					± 0.2			± 0.2	V					
Voc	Common-mode output voltage [#]	R _L = 100 Ω,	R _L = 100 Ω,	R _L = 100 Ω,	R _L = 100 Ω,	R _L = 100 Ω,	R _L = 100 Ω,	See Figure 1			±3			±3	V
	Change in magnitude of common-mode output voltage¶					± 0.2			±0.2	<					
	Output current with nower off		V _O = 6 V			100			100						
U U	Output current with power on	VCC = 0	vCC = 0	$V_{O} = -0.25 V$			-100			-100	μΑ				
107	Off-state (high-impedance		$V_{O} = 0.5 V$			-20			-20						
102	state) output current		V _O = 2.5 V			20			20	μΛ					
I	Input current at maximum input voltage	V _{CC} = MAX,	V _I = 7 V			100			100	μΑ					
IIH	High-level input current	$V_{CC} = MAX,$	V _I = 2.7 V			20			20	μΑ					
۱ _{IL}	Low-level input current	$V_{CC} = MAX,$	$V_I = 0.4 V$			- 200			- 200	μΑ					
IOS	Short-circuit output current	$V_{CC} = MAX$		- 30		-150	- 30		- 150	mA					
ICC	Supply current (all drivers)	V _{CC} = MAX, All outputs dis	abled		26	45		26	45	mA					

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] All typical values are at V_{CC} = 5 V and T_A = 25°C. § The minimum V_{OD2} with a 100- Ω load is either 1/2 V_{OD1} or 2 V, whichever is greater.

I VOD | and VOC | are the changes in magnitude of VOD and VOC, respectively, that occur when the input is changed from a high level to a low level.

In ANSI Standard EIA/TIA-422-B, VOC, which is the average of the two output voltages with respect to ground, is called output offset voltage, VOS-

I Not more than one output should be shorted at a time, and duration of the short circuit should not exceed one second.

switching characteristics, $V_{CC} = 5 V$, $T_A = 25^{\circ}C$ (see Figure 2)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
^t PLH	Propagation delay time, low-to-high-level output			6	13	ns
^t PHL	Propagation delay time, high-to-low-level output	S1 and S2 open, $C_L = 30 \text{ pF}$		9	14	ns
	Output-to-output skew			3	6	ns
^t PZH	Output enable time to high level	S1 open and S2 closed		11	15	ns
^t PZL	Output enable time to low level	S1 closed and S2 open		16	20	ns
^t PHZ	Output disable time from high level	S1 open and S2 closed, $C_L = 10 \text{ pF}$		8	15	ns
^t PLZ	Output disable time from low level	S1 and S2 closed, $C_L = 10 \text{ pF}$		18	20	ns



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PARAMETER MEASUREMENT INFORMATION







VOLTAGE WAVEFORMS



TEST CIRCUIT

- NOTES: A. When measuring propagation delay times and skew, switches S1 and S2 are open.
 - B. Each enable is tested separately.
 - C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - D. C_L includes probe and jig capacitance.
 - E. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O \approx 50 Ω , t_f \leq 15 ns, and t_f \leq 6 ns.

Figure 2. Test Circuit and Voltage Waveforms



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TYPICAL CHARACTERISTICS[†]

Figure 5

Figure 6

[†] Data for temperatures below 0°C and above 70°C and below 4.75 V and above 5.25 V are applicable to SN55ALS192 circuits only.



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[†] Data for temperatures below 0°C and above 70°C, and below 4.75 V and above 5.25 V, are applicable to SN55ALS192 circuits only.
 NOTES: A. The A input is connected to V_{CC} during the testing of the Y outputs and to ground during the testing of the Z outputs.
 B. The A input is connected to GND during the testing of the Y outputs and to V_{CC} during the testing of the Z outputs.



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TYPICAL CHARACTERISTICS[†]





[†] Data for temperatures below 0°C and above 70°C, and below 4.75 V and above 5.25 V, are applicable to SN55ALS192 circuits only.



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Figure 15



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